Search Notes

Application/Control	No.	

Applicant(s)/Patent under Reexamination

RONKKO ET AL.

10/766,519

Examiner

Art Unit

LUN-YI LAO

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SEARCHED				
Class	Subclass	Date	Examiner	
345	173-183			
178	19.01			
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	19.05			
	19.06			
	19.07			
463	37-38	8/20/2006	LL	

INTERFERENCE SEARCHED				
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